Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,545,352 B1	04-2003	Ruckdeschel, Thomas W.	257/718
	В	US-5,548,090 A	08-1996 `	Harris, Mark R.	174/252
	С	US-6,373,700 B1	04-2002	Wang, Feng Ku	361/698
	D	US-6,408,934 B1	06-2002	Ishida et al.	165/80.3
	Ε	US-6,257,328 B1	07-2001	Fujiwara et al.	165/185
	F	US-6,060,166 A	05-2000	Hoover et al.	428/408
	G	US-6,328,097 B1	12-2001	Bookhardt et al	165/104.33
	, н	US-5,560,423 A	10-1996	Larson et al.	165/104.26
	ı	US-			
	J	US-			
	Ķ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	199 25 983	12-2000	DE .	Goebel et al.	165/185
	0	40 04 457	08-1991	DE	Locker	165/185
	Р					
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.